

Notice of References Cited		Application/Control No.	Applicant(s)/Patent Under Reexamination CHANG ET AL.	
		Examiner James A. Dudek	Art Unit 2871	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-2004/0227458 A1	11-2004	He et al.	313/504
	B	US-2004/0189167 A1	09-2004	Adachi et al.	313/501
	C	US-2004/0051445 A1	03-2004	Adachi, Masaya	313/504
	D	US-2002/0079831 A1	06-2002	He et al.	313/504
	E	US-6,710,541 B2	03-2004	He et al.	313/504
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.